



Infrared  
Product Data Sheet  
LTE- 15A3L-HP

Spec No. :DS50-2017-0089  
Effective Date: 11/07/2017  
Revision: -

**LITE-ON DCC**

**RELEASE**

**BNS-OD-FC001/A4**

## IR Emitter LTE-15A3L-HP

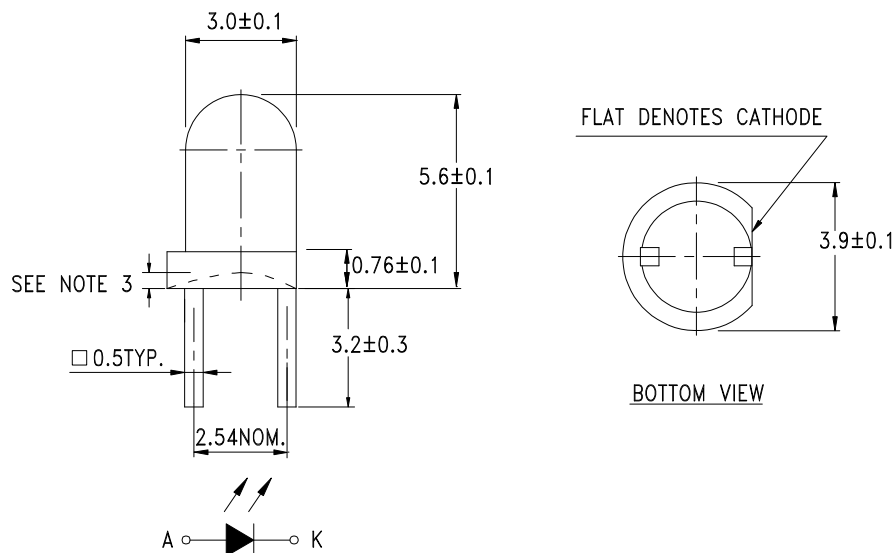
### 1. Description

Lite-On offers a broad range of discrete infrared components for application such as remote control, IR wireless data transmission, security alarm & etc. Customers need infrared solutions featuring high power, high speed and wide viewing angles. The product line includes GaAs 940nm IREDs, AlGaAs high speed 850nm IREDs, PIN Photodiodes and Phototransistors. Photodiodes and Phototransistors can be provided with a filter that reduces digital light noise in the sensor function, which enables a high signal-to-noise ratio.

#### 1.1. Features

- SELECTED TO SPECIFIC On-LINE INTENSITY AND RADIANT INTENSITY RANGES
- HIGH POWER
- LOW COST PLASTIC PACKAGE
- CLEAR TRANSPARENT COLOR PACKAGE

### 2. Outline Dimensions



#### Notes :

1. All dimensions are in millimeters.
2. Tolerance is  $\pm 0.25 \text{ mm}$  unless otherwise noted.
3. Surface concave resin under flange is  $0.5 \text{ mm}$  max.
4. Specifications are subject to change without notice.
5. Lead spacing is measured where the leads emerge from the package.

## IR Emitter LTE-15A3L-HP

### 3. Absolute Maximum Ratings at TA=25°C

Parameter	Maximum Rating	Unit
Power Dissipation	90	mW
Peak Forward Current (300pps, 10µs pulse)	1	A
Continuous Forward Current	60	mA
Reverse Voltage	5	V
Operating Temperature Range	-40°C to + 85°C	
Storage Temperature Range	-55°C to + 100°C	
Lead Soldering Temperature [1.6mm(.063") From Body]	260°C for 5 Seconds	

### 4. Electrical / Optical Characteristics at TA=25°C

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Condition	BIN NO.
Radiant Intensity *see note (1) & (2)	I <sub>E</sub>	10*	-	12.7*	mW/sr	I <sub>F</sub> = 20mA	A
		12.7*	-	13.5*			B
		13.5*	-	32*			C
Forward Voltage	V <sub>F</sub>			1.65	V	I <sub>F</sub> = 20mA	
Peak Emission Wavelength	λ <sub>Peak</sub>		940		nm	I <sub>F</sub> = 20mA	
Spectral Line Half-Width	Δ λ		50		nm	I <sub>F</sub> = 20mA	
Reverse Current *see note (3)	I <sub>R</sub>			10	µA	V <sub>R</sub> = 5V	
Viewing Angle (See FIG.6)	2θ <sub>1/2</sub>		45		deg.		
Rise Time	T <sub>r</sub>		20		ns	I <sub>F</sub> =20mA	
Fall Time	T <sub>f</sub>		20		ns		

**NOTE:**

(1): The \* values provided here are for reference at preliminary stage. It will be fine-tuned again to best fit the actual yield situation.

(2): IE bin limits should be included with ±10% testing tolerance.

(3): The reverse voltage (V<sub>r</sub>) condition is only for testing purpose. This device is not designed for reverse current operation.

**IR Emitter**  
**LTE-15A3L-HP**

**5. Typical Electrical / Optical Characteristics Curves**

(25°C Ambient Temperature Unless Otherwise Noted)

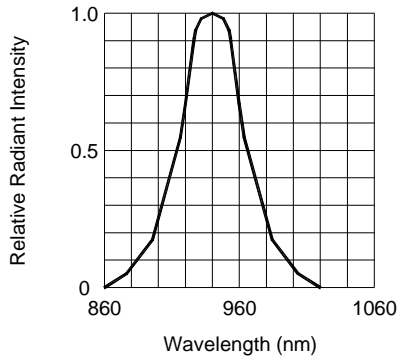


FIG.1 SPECTRAL DISTRIBUTION

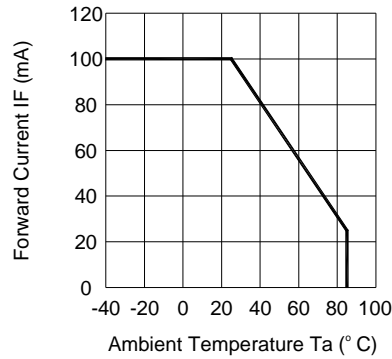


FIG.2 FORWARD CURRENT VS. AMBIENT TEMPERATURE

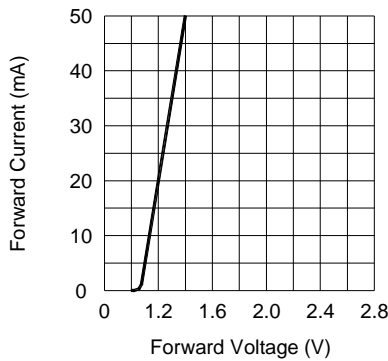


FIG.3 FORWARD CURRENT VS. FORWARD VOLTAGE

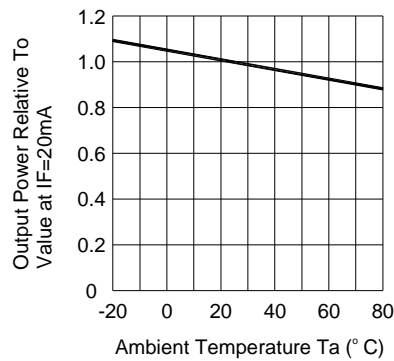


FIG.4 RELATIVE RADIANT INTENSITY VS. AMBIENT TEMPERATURE

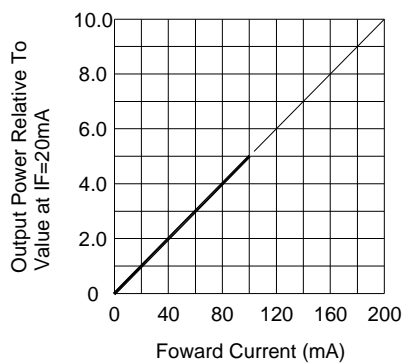


FIG.5 RELATIVE RADIANT INTENSITY VS. FORWARD CURRENT

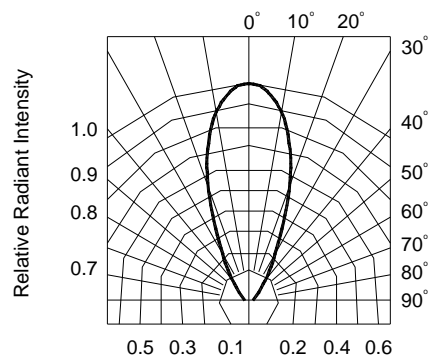


FIG.6 RADIATION DIAGRAM

## IR Emitter LTE-15A3L-HP

### 6. CAUTIONS

#### 6.1. Application

The PTDs (photodiode) described here are intended to be used for ordinary electronic equipment (such as sensor or detector). Consult Liteon's Sales in advance for information on applications in which exceptional reliability is required, particularly when the failure or malfunction of the PTDs may directly jeopardize life or health (such as in aviation, transportation, traffic control equipment, medical and life support systems and safety devices).

#### 6.2. Storage

The storage ambient for the PTDs should not exceed 30°C temperature and 70% relative humidity. It is recommended that PTDs out of their original packaging are used within three months. For extended storage out of their original packaging, it is recommended that the PTDs be stored in a sealed container with appropriate desiccant or in desiccators with nitrogen ambient.

#### 6.3. Cleaning

Use alcohol-based cleaning solvents such as isopropyl alcohol to clean the PTDs if necessary.

#### 6.4. Lead Forming & Assembly

During lead forming, the leads should be bent at a point at least 3mm from the base of PTD lens. Do not use the base of the lead frame as a fulcrum during forming. Lead forming must be done before soldering, at normal temperature. During assembly on PCB, use minimum clinch force possible to avoid excessive mechanical stress.

#### 6.5. Soldering

When soldering, leave a minimum of 3mm clearance from the base of the lens to the soldering point. Dipping the lens into the solder must be avoided. Do not apply any external stress to the lead frame during soldering while the PTD is at high temperature.

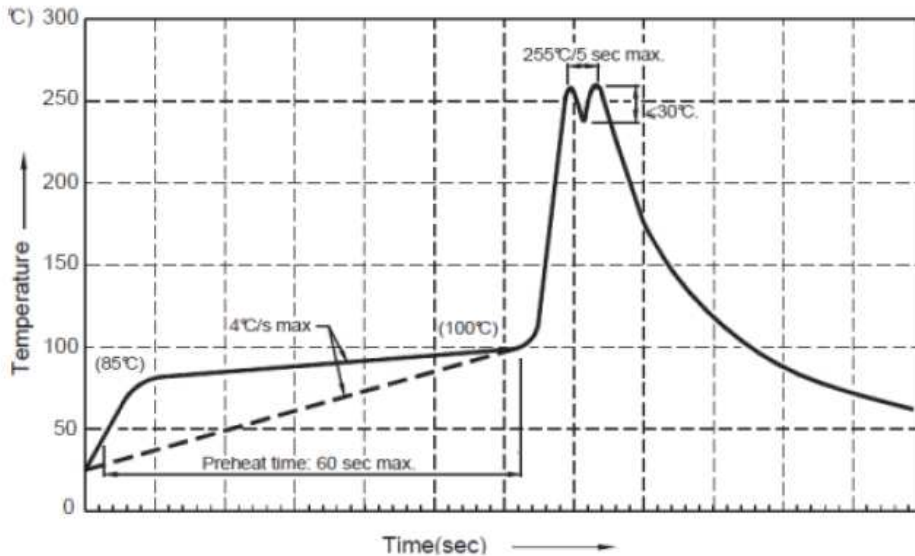
#### Recommended soldering conditions:

Soldering iron		Wave soldering	
Temperature	350°C Max.	Pre-heat	100°C Max.
Soldering time	3 seconds Max. (one time only)	Pre-heat time	60 seconds Max.
Position	No closer than 2mm from the base of the epoxy bulb	Solder wave	260°C Max.
		Soldering time	5 seconds Max.
		Dipping Position	No lower than 2mm from the base of the epoxy bulb

Note: Excessive soldering temperature and/or time might result in deformation of the PTD lens or catastrophic failure of the PTD. IR reflow is not suitable process for through hole lamp product.

## IR Emitter LTE-15A3L-HP

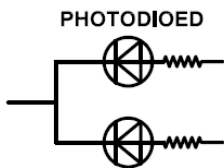
### Reference for Lead-Free Wave Soldering Profile



### 6.6. Drive Method

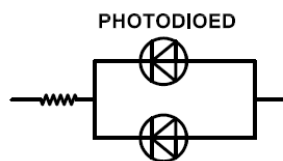
A PTD is a voltage-operated device. In order to ensure photocurrent uniformity on multiple PTDs connected in parallel in an application, it is recommended that a current limiting resistor be incorporated in the drive voltage, in series with each PTD as shown in Circuit A below.

#### Circuit model (A)



(A) Recommended circuit

#### Circuit model (B)



(B) The light current of each PTD might appear different due to the differences in the I-V characteristics of those PTDs.

### 6.7. ESD (Electrostatic Discharge)

**Static Electricity or power surge will damage the device.**

**Suggestions to prevent ESD damage:**

- Use a conductive wrist band or anti- electrostatic glove when handling these devices
- All devices, equipment, and machinery must be properly grounded
- Work tables, storage racks, etc. should be properly grounded
- Use ion blower to neutralize the static charge which might have built up on surface of the devices plastic lens as a result of friction between devices during storage and handing

**Suggested checking list:**

## IR Emitter LTE-15A3L-HP

### Training and Certification

- 6.7.1.1. Everyone working in a static-safe area is ESD-certified?
- 6.7.1.2. Training records kept and re-certification dates monitored?

### Static-Safe Workstation & Work Areas

- 6.7.2.1. Static-safe workstation or work-areas have ESD signs?
- 6.7.2.2. All surfaces and objects at all static-safe workstation and within 1 ft measure less than 100V?
- 6.7.2.3. All ionizer activated, positioned towards the units?
- 6.7.2.4. Each work surface mats grounding is good?

### Personnel Grounding

- 6.7.3.1. Every person (including visitors) handling ESD sensitive (ESDS) items wear wrist strap, heel strap or conductive shoes with conductive flooring?
- 6.7.3.1. If conductive footwear used, conductive flooring also present where operator stand or walk?
- 6.7.3.2. Garments, hairs or anything closer than 1 ft to ESD items measure less than 100V\*?
- 6.7.3.3. Every wrist strap or heel strap/conductive shoes checked daily and result recorded for all DLs?
- 6.7.3.4. All wrist strap or heel strap checkers calibration up to date?

### Device Handling

- 6.7.4.1. Every ESDS items identified by EIA-471 labels on item or packaging?
- 6.7.4.2. All ESDS items completely inside properly closed static-shielding containers when not at static-safe workstation?
- 6.7.4.3. No static charge generators (e.g. plastics) inside shielding containers with ESDS items?
- 6.7.4.4. All flexible conductive and dissipative package materials inspected before reuse or recycle?

### Others

- 6.7.5.1. Audit result reported to entity ESD control coordinator?
- 6.7.5.2. Corrective action from previous audits completed?
- 6.7.5.3. Are audit records complete and on file?

## IR Emitter LTE-15A3L-HP

### 7. Reliability Test

Classification	Test Item	Test Condition	Reference Standard
Endurance Test	High Temperature High Humidity Reverse Bias	Ta= 65°C RH= 95% VR=5V Test Time= 500HRS	MIL-STD-750D:1026 (1995) MIL-STD-883G:1005 (2006)
	High Temperature High Humidity storage	Ta= 65°C RH= 95% Test Time= 240HRS	MIL-STD-202G:103B (2002) JEITA ED-4701:100 103 (2001)
	High Temperature Storage	Ta= 105±5°C Test Time= 1000HRS	MIL-STD-750D:1031 (1995) MIL-STD-883G:1008 (2006) JEITA ED-4701:200 201 (2001)
	Low Temperature Storage	Ta= -55±5°C Test Time=1000HRS	JEITA ED-4701:200 202 (2001)
Environmental Test	Temperature Cycling	-55°C ~ 25°C ~ 105°C ~ 25°C 30mins 5mins 30mins 5mins Test time: 30 Cycles	MIL-STD-750D:1051 (1995) MIL-STD-883G:1010 (2006) JEITA ED-4701:100 105 (2001) JESD22-A104C (2005)
	Thermal Shock	105 ± 5°C ~ -55°C ± 5°C 10mins 10mins Test time: 20 Cycles	MIL-STD-750D:1056 (1995) MIL-STD-883G:1011 (2006) MIL-STD-202G:107G (2002) JESD22-A106B (2004)
	Solder Resistance	T.sol = 260 ± 5°C Dwell Time= 10±1 seconds 3mm from the base of the epoxy bulb	MIL-STD-750D:2031(1995) JEITA ED-4701: 300 302 (2001)
	Solder Ability	T. sol = 245 ± 5°C Dwell Time= 5 ± 0.5 seconds (Lead Free Solder, Coverage ≥ 95% of the dipped surface)	MIL-STD-750D:2026 (1995) MIL-STD-883G:2003 (2006) MIL-STD-202G:208H (2002) IPC/EIA J-STD-002 (2004)

### 8. Others

The appearance and specifications of the product may be modified for improvement, without prior notice.



单击下面可查看定价，库存，交付和生命周期等信息

[>>Lite-On\(光宝\)](#)